

Data sheet acquired from Harris Semiconductor SCHS034C – Revised October 2003

# CMOS Presettable Up/Down Counter

Binary or BCD-Decade
High-Voltage Types (20-Volt Rating)

■ CD4029B consists of a four-stage binary or BCD-decade up/down counter with provisions for look-ahead carry in both counting modes. The inputs consist of a single CLOCK, CARRY-IN (CLOCK ENABLE), BINARY/DECADE, UP/DOWN, PRESET ENABLE, and four individual JAM signals. Q1, Q2, Q3, Q4 and a CARRY OUT signal are provided as outputs.

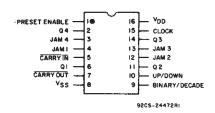
A high PRESET ENABLE signal allows information on the JAM INPUTS to preset the counter to any state asynchronously with the clock. A low on each JAM line, when the PRESET-ENABLE signal is high, resets the counter to its zero count. The counter is advanced one count at the positive transition of the clock when the CARRY-IN and PRE-SET ENABLE signals are low. Advancement is inhibited when the CARRY-IN or PRESET ENABLE signals are high. The CARRY-OUT signal is normally high and goes low when the counter reaches its maximum count in the UP mode or the minimum count in the DOWN mode provided the CARRY-IN signal is low. The CARRY-IN signal in the low state can thus be considered a CLOCK ENABLE. The CARRY-IN terminal must be connected to VSS when not in use.

Binary counting is accomplished when the BINARY/DECADE input is high; the counter counts in the decade mode when the BINARY/DECADE input is low. The counter counts up when the UP/DOWN input is high, and down when the UP/DOWN input is low. Multiple packages can be connected in either a parallel-clocking or a ripple-clocking arrangement as shown in Fig. 17.

Parallel clocking provides synchronous control and hence faster response from all counting outputs. Ripple-clocking allows for longer clock input rise and fall times.

The CD4029B-series types are supplied in 16-lead hermetic dual-in-line ceramic packages (F3A suffix), 16-lead dual-in-line plastic packages (E suffix), 16-lead small-outline packages (M, M96, MT, and NSR suffixes), and 16-lead thin shrink small-outline packages (PW and PWR suffixes).

#### CD4029B Terminal Diagram



# CD4029B Types

#### Features:

- Medium-speed operation . . . 8 MHz (typ.)
   © C<sub>L</sub> = 50 pF and V<sub>DD</sub>-V<sub>SS</sub> = 10 V
- Multi-package parallel clocking for synchronous high speed output response or ripple clocking for slow clock input rise and fall times
- "Preset Enable" and individual "Jam" inputs provided
- Binary or decade up/down counting
- BCD outputs in decade mode
- 100% tested for quiescent current at 20 V
- 5-V, 10-V, and 15-V parametric ratings
- Standardized, symmetrical output characteristics
- Maximum input current of 1 μA at 18 V over full package-temperature range; 100 nA at 18 V and 25°C
- Noise margin (over full package-temperature range)

1 V at VDD = 5 V

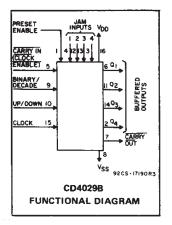
2 V at V<sub>DD</sub> = 10 V

2.5 V at V<sub>DD</sub> = 15 V

 Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

#### Applications:

- Programmable binary and decade counting/frequency synthesizers-BCD output
- Analog to digital and digital to analog conversion
- Up/Down binary counting
- Magnitude and sign generation
- Up/Down decade counting
- Difference counting



RECOMMENDED OPERATING CONDITIONS at  $T_A = 25^{\circ}$ C, Except as Noted. For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	3	V <sub>DD</sub>	LIN	UNITS	
		(V)	Min.	Max.	
Supply-Voltage Ran Temperature Rang	nge (For T <sub>A</sub> = Full Package- le)		3	18	V
Setup Time t <sub>SU</sub> : Càrry-In		5 10 15	200 70 60	_ _ _	
U/D or B/D		5 10 15	340 140 100	- - -	ns
Clock Pulse Width,	tw.	5 10 15	180 90 60	- - -	
Preset Enable Pulse	Width, t <sub>W</sub>	5 10 15	130 70 50	- - -	
Clock Input Freque	ncy, fCL	5 10 15	_ _ _	2 4 5.5	MHz
Clock Rise and Fall	Time, t <sub>r</sub> CL, t <sub>f</sub> CL	5 10 15	- - -	15	μs

# CD4029B Types

MAXIMUM RATINGS, Absolute-Maximum Values: DC SUPPLY-VOLTAGE RANGE, (VDD)	
Voltages referenced to VSS Terminal)	0.5V to +20V
INPUT VOLTAGE RANGE, ALL INPUTS	0.5V to V <sub>DD</sub> +0.5V
DC INPUT CURRENT, ANY ONE INPUT	±10mA
POWER DISSIPATION PER PACKAGE (PD):	
For T <sub>A</sub> = -55°C to +100°C	500mW
For T <sub>A</sub> = +100°C to +125°C	
	Dorald Embanky at 12mm, O to 200mm
DEVICE DISSIPATION PER OUTPUT TRANSISTOR	
DEVICE DISSIPATION PER OUTPUT TRANSISTOR FOR TA = FULL PACKAGE-TEMPERATURE RANGE (All Package)	Types)100mW
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DEVICE DISSIPATION PER OUTPUT TRANSISTOR FOR $T_A$ = FULL PACKAGE-TEMPERATURE RANGE (All Package OPERATING-TEMPERATURE RANGE ( $T_A$ )	Types)

STATIC ELECTRICAL	<b>CHARACTERISTICS</b>

CHARAC- TERISTIC	CONDITIONS LIMITS AT INDICATED TEMPERATURES (°C)								C)	U N I T	
	v <sub>o</sub>	VIN	V <sub>DD</sub>					+25			s
	(V)	(V)	(V)	-55	-40	+85	+125	Min.	Тур.	Max.	
Quiescent		0,5	5	5	5	150	150	_	0.04	5	
Device		0,10	10	10	10	300	300	_	0.04	10	μΑ
Current,	-	0,15	15	20	20	600	600	_	0.04	20	
100		0,20	20	100	100	3000	3000	_	0.08	100	
Output Low	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	-	
(Sink) Current	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	_	
I <sub>OL</sub> Min.	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	-	
Output High (Source) Current,	4.6	0,5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1	_	mΑ
	2.5	0,5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	_	
	9.5	0,10	10	-1.6	-1.5	-1.1	-0.9	-1.3	-2.6	_	
IOH Min.	13.5	0,15	15	-4.2	-4	-2.8	- 2.4	-3.4	-6.8	-	
Output Voltage:		0,5	5		0.		0	0.05			
Low-Level,	-	0,10	10		0	.05	·		0	0.05	
VOL Max.	_	0,15	15		0.	-	0	0.05	V		
Output		0,5	5		4.	4.95	5	_			
Voltage: High-Level,	_	0,10	10		9.	95		9.95	10	-	
VOH Min.	_	0,15	15		14.	.95		14.95	15	_	
Input Low	0.5,4.5	-	5			1.5		_		1.5	
Voltage	1,9		10			3		-		3	
V <sub>IL</sub> Max.	1.5,13.5	_	15			4		_	_	4	v
Input High	0.5,4.5		5		3	3.5		3.5	_	_	
Voltage,	1,9	_	10	7				7	_	_	]
V <sub>IH</sub> Min.	1.5,13.5	1	15			11		11	_		
Input Current I <sub>IN</sub> Max.	_	0,18	18	±0.1	±0.1	±1	±1	_	±10 <sup>-5</sup>	±0.1	μА

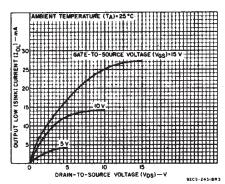


Fig. 1 — Typical output low (sink) current characteristics.

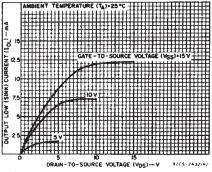


Fig. 2 — Minimum output low (sink) current characteristics.

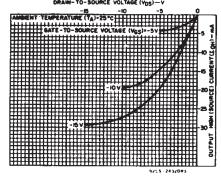


Fig. 3 - Typical output high (source) current characteristics.

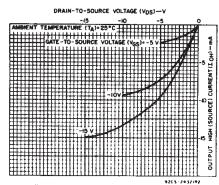


Fig. 4 — Minimum output high (source) current characteristics.

## CD4029B Types

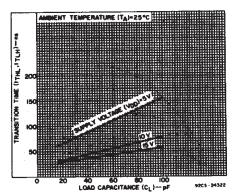


Fig. 5 — Typical transition time as a function of load capacitance.

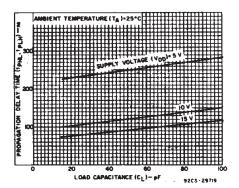


Fig. 6 — Typical propagation delay times as a function of load capacitance (Q output).

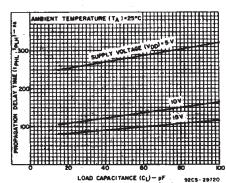


Fig. 7 — Typical propagation delay time as a function of load capacitance (carry output).

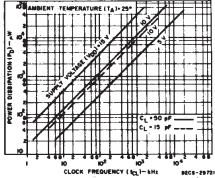
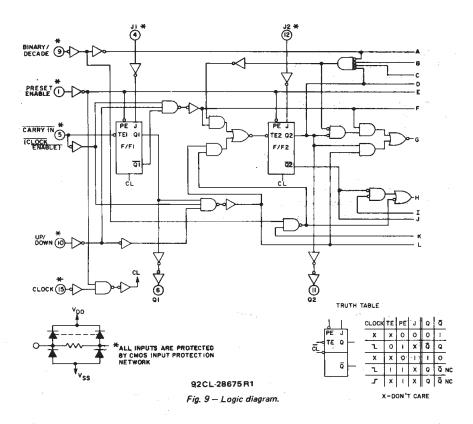


Fig. 8 – Typical power dissipation as a function of frequency.



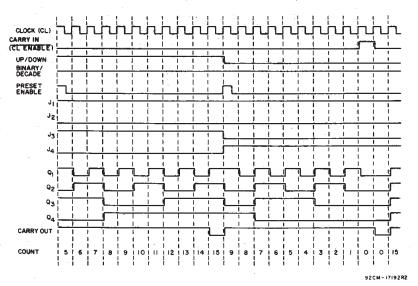


Fig. 10 - Timing diagram-binary mode.

I CD40II QUAD 2 INPUT NAND GATE

92CS-1719\$R2

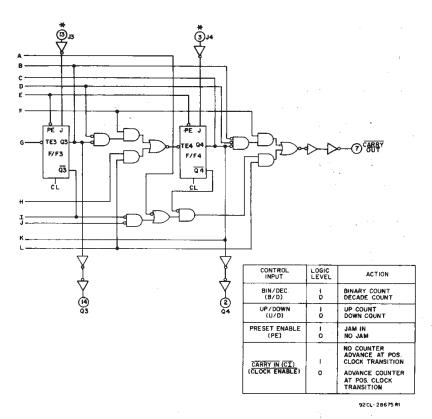
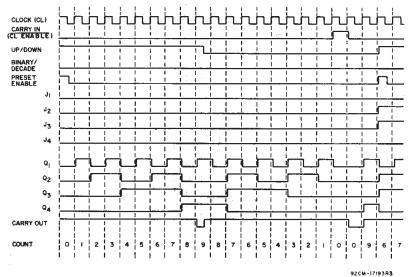


Fig. 9 - Logic diagram (cont'd).

Fig. 11 — Conversion of clock up, clock down input signals to clock and up/down input signals.

The CD4029B CLOCK and UP/DOWN inputs are used directly in most applications. In applications where CLOCK UP and CLOCK DOWN inputs are provided, conversion to the CD4029B CLOCK and UP/DOWN inputs can easily be realized by use of the circuit in Fig. 11.

CD4029B changes count on positive transitions of CLOCK UP or CLOCK DOWN inputs. For the gate configuration shown below, when counting up the CLOCK DOWN input must be maintained high and conversely when counting down the CLOCK UP input must be maintained high.



CD4029B Types

Fig. 12 - Timing diagram-decade mode.

# CD4029B Types

# DYNAMIC ELECTRICAL CHARACTERISTICS at T\_A = 25°C, input t\_f, t\_f = 20 ns, C\_ = 50 pF, R\_ = 200 k $\Omega$

CHARACTERISTIC	TEST CO	NDITIONS	ı	UNITS				
		V <sub>DD</sub> (V)	Min.	Тур.	Max.			
Clocked Operation	.,							
Propagation Delay Time: tpHL, tpLH		5	_	250	500			
Q Output		10	_	120	240			
		15	_	90	180			
		5	_	280	560			
Carry Output		10	-	130	260			
		15	_	95	190	ns		
		5	-	100	200			
Transition Time: t <sub>THL</sub> , t <sub>TLH</sub>		10	-	50	100			
Q Outputs, Carry Output		15	_	40	80			
		5	-	90	180			
Minimum Clock Pulse Width, tw		10	_	45	90			
		15	-	30	60			
		5	_	_	15			
Clock Rise & Fall Time, t <sub>F</sub> CL, t <sub>f</sub> CL**		10	_	-	15	μs		
· '		15		_	15	'		
*		5	_	170	340			
Minimum Setup Times, ts		10	_	70	140	ns		
8/D or U/D		15	_	50	100			
		5	2	4	_			
Maximum Clock Input Frequency, fCL		10	4	8	_	MHz		
		15	5.5	11	-			
Input Capacitance, C <sub>IN</sub>	Any Input	t	-	5	7.5	ρF		
Preset Enable								
		5		235	470			
Propagation Delay Time: tpHL, tpLH	<u> </u>	10	-	100	200			
Q Outputs	İ	15	_	80	160			
		5		320	640			
Carry Output	İ	10		145	290			
	1	15		105	210	-		
	1	5		65	130	ns		
Minimum Preset Enable Pulse Width, tw	ŀ	10		35	70			
"	<u> </u>	15	-	25	50			
Marine D	Ì	5	_	100	200			
Minimum Preset Enable Removal Time, tron *	1	10	_	55	110			
rime, <sup>t</sup> rem*	1	15	-	40	80			
Carry Input								
Propagation Delay Time: tpHL, tpLH		5	_	170	340			
Carry Output		10	_	70	140	ns		
· · ·		15		50	100			
Min. HOLD Time	Ī	5	-	25	50	ns		
tµ*** Carry In	1	10		15	30			
	1	15	_	12	25	•		
Min Set-Up Time		5	_	100	200	ns		
t <sub>s</sub> *** Carry in	İ	10	_	35	70			
a	ł	15		30	60			

<sup>\*</sup> From Up/Down, Binary/Decode, Carry In, or Preset Enable Control Inputs to Clock Edge.

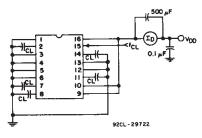


Fig. 13 - Power dissipation test circuit.

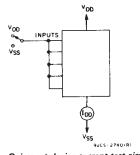


Fig. 14 - Quiescent-device current test circuit.

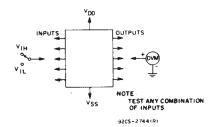


Fig. 15 - Input voltage test circuit.

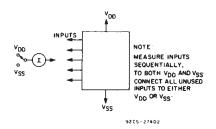


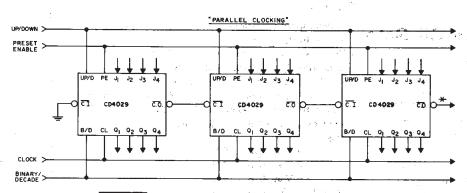
Fig. 16 - Input current test circuit.

<sup>\*\*\*\*</sup>From Up/Lown, Binary/Jecode, Carry In, or Preset Enable Control injuris to Glock Edge.

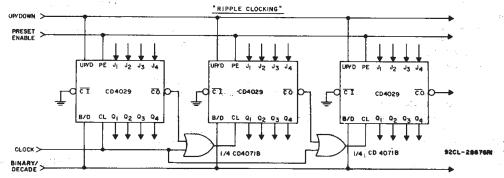
\*\*\*If more than one unit is cascaded in the parallel clocked application, t<sub>v</sub>CL should be made less than or equal to the sum of the fixed propagation delay at 15 pF and the transition time of the carry output driving stage for the estimated capacitive load. This measurement was made with a decoupling capacitor (>1 µF) between V<sub>DD</sub> and V<sub>SS</sub>.

\*\*\*From Carry In to Clock Edge

#### CD4029B Types



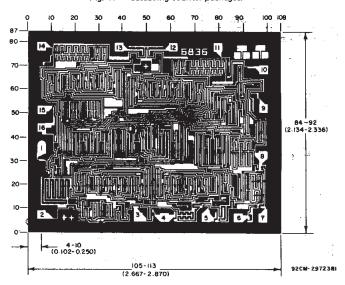
\* CARRY OUT lines at the 2nd, 3rd, etc., stages may have a negative-going glitch pulse resulting from differential delays of different CD40298 fC's. These negative-going glitches do not affect proper CD40298 operation. However, if the CARRY OUT signals are used to trigger other edge-sensitive logic devices, such as FF's or counters, the CARRY OUT signals should be gated with the clock signal using a 2-input OR gate such as CD40718.



Ripple Clocking Mode:

The Up/Down control can be changed at any count. The only restriction on changing the Up/Down control is that the clock input to the first counting stage must be high. For cascading counters operating in a fixed up-count or down-count mode, the OR gates are not required between stages, and  $\overline{CO}$  is connected directly to the CL input of the next stage with  $\overline{CI}$  grounded.

Fig. 17 - Cascading counter packages.



Chip dimensions and pad layout for CD4029B

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils ( $10^{-3}$  inch).

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#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking
•	( )	( )			(-)	(4)	(5)		(-/
8101602EA	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	8101602EA CD4029BF3A
CD4029BE	Active	Production	PDIP (N)   16	25   TUBE	Yes	NIPDAU	N/A for Pkg Type	-55 to 125	CD4029BE
CD4029BF	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	CD4029BF
CD4029BF3A	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	8101602EA CD4029BF3A
CD4029BM	Obsolete	Production	SOIC (D)   16	-	-	Call TI	Call TI	-55 to 125	CD4029BM
CD4029BM96	Active	Production	SOIC (D)   16	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4029BM
CD4029BNSR	Active	Production	SOP (NS)   16	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4029B
CD4029BPWR	Active	Production	TSSOP (PW)   16	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CM029B

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and

<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

## **PACKAGE OPTION ADDENDUM**

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continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF CD4029B, CD4029B-MIL:

■ Military : CD4029B-MIL

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

# **PACKAGE MATERIALS INFORMATION**

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#### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD4029BM96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD4029BNSR	SOP	NS	16	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
CD4029BPWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1



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#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD4029BM96	SOIC	D	16	2500	353.0	353.0	32.0
CD4029BNSR	SOP	NS	16	2000	356.0	356.0	35.0
CD4029BPWR	TSSOP	PW	16	2000	356.0	356.0	35.0

# **PACKAGE MATERIALS INFORMATION**

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#### **TUBE**



#### \*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
CD4029BE	N	PDIP	16	25	506	13.97	11230	4.32
CD4029BE	N	PDIP	16	25	506	13.97	11230	4.32



SOP



- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing
- per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm, per side.



SOF



#### NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOF



#### NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



# D (R-PDS0-G16)

## PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.





SMALL OUTLINE PACKAGE



- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



## **MECHANICAL DATA**

# NS (R-PDSO-G\*\*)

# 14-PINS SHOWN

#### PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



## 14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

# N (R-PDIP-T\*\*)

# PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



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